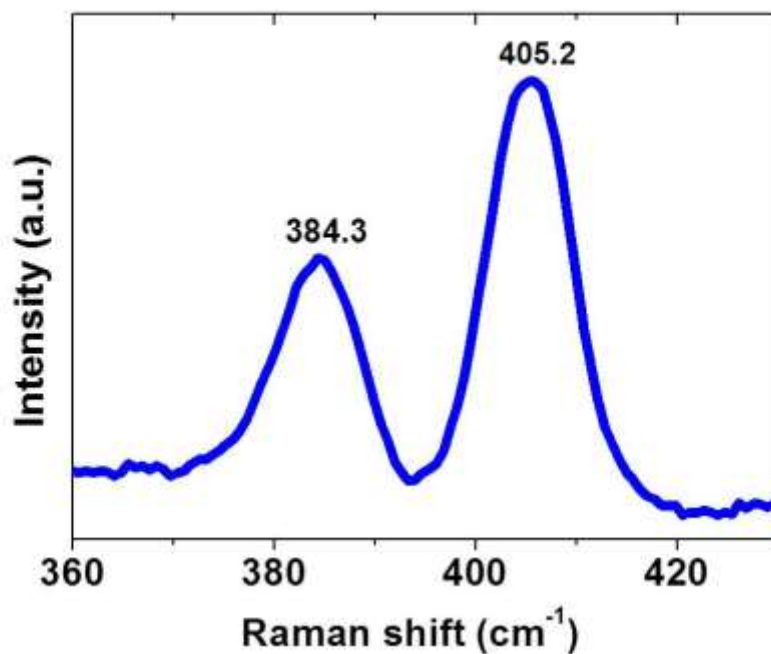
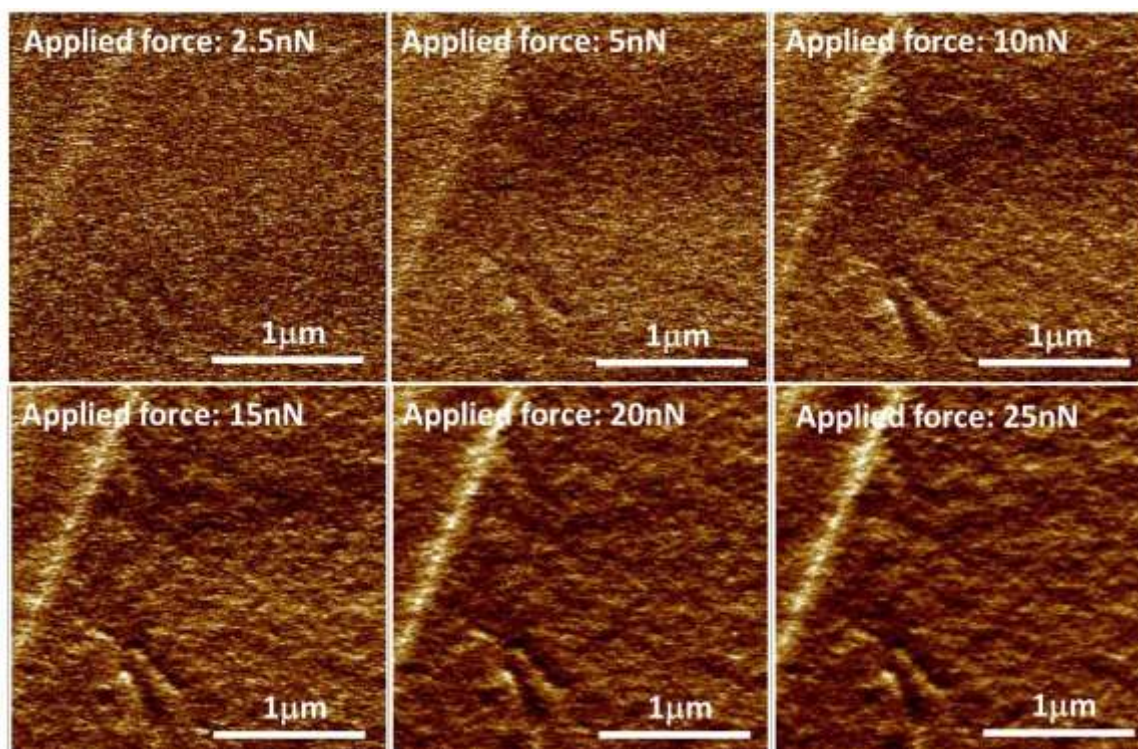


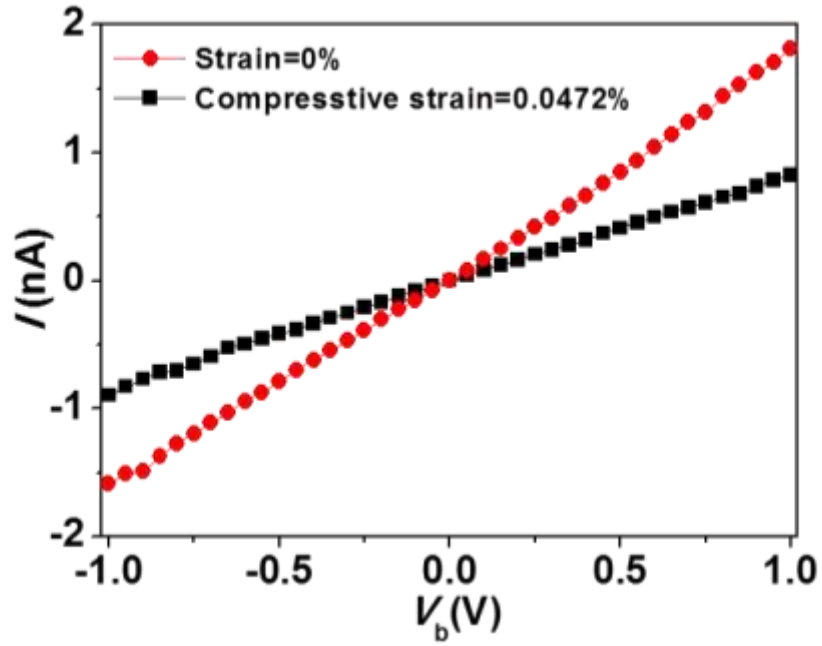
Supplementary Figure 1 TEM-based energy dispersive spectroscopy (TEM-EDS) analysis of the composition ratio of monolayer MoS₂ triangles.



Supplementary Figure 2 Raman spectra for the transferred monolayer MoS₂ on silicon dioxide.



Supplementary Figure 3 Deformation images acquired over a $2.5 \times 2.5 \mu\text{m}^2$ area in the central region of MoS₂ device under variable mechanical loading forces applied by AFM tip.



Supplementary Figure 4 I - V_b curves for the highest gauge factor of 1160 in our CVD monolayer MoS₂ strain sensor under free of strain and a mechanical load equivalent to 10nN (strain=0.0472%).